### SN54HC266, SN74HC266 QUADRUPLE 2-INPUT EXCLUSIVE-NOR GATES WITH OPEN-DRAIN OUTPUTS SCLS135C - DECEMBER 1982 - REVISED MAY 1997

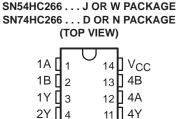
 Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

### description

The 'HC266 are composed of four independent 2-input exclusive-NOR gates and feature open-drain outputs. They perform the Boolean function  $Y = \overline{A \otimes B}$  or  $Y = A\overline{B} + A\overline{B}$  in positive logic.

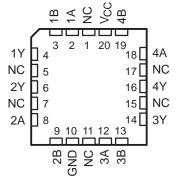
The SN54HC266 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The SN74HC266 is characterized for operation from  $-40^{\circ}$ C to 85°C.

FUNCTION TABLE							
INP	UTS	OUTPUT					
Α	В	Y					
L	L	Н					
L	Н	L					
н	L	L					
н	Н	н					



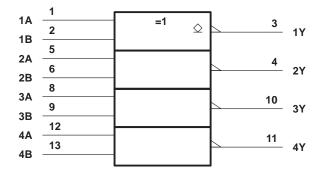
2A 5 10 3Y 2B 6 9 3B GND 7 8 3A

SN54HC266 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

## logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, and W packages.

## logic diagram, each gate (positive logic)





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# SN54HC266, SN74HC266 QUADRUPLE 2-INPUT EXCLUSIVE-NOR GATES WITH OPEN-DRAIN OUTPUTS

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## absolute maximum ratings over operating free-air temperature range<sup>†</sup>

Supply voltage range, V <sub>CC</sub>	
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0 or V <sub>I</sub> > V <sub>CC</sub> ) (see Note 1)	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> ) (see Note 1)	±20 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±25 mA
Continuous current through V <sub>CC</sub> or GND	
Package thermal impedance, $\theta_{JA}$ (see Note 2): D package	
N package	
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

### recommended operating conditions

			SI	SN54HC266		SN74HC266			LINUT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		2	5	6	2	5	6	V
	V <sub>IH</sub> High-level input voltage	$V_{CC} = 2 V$	1.5			1.5			V
VIH		$V_{CC} = 4.5 V$	3.15			3.15			
		$V_{CC} = 6 V$	4.2		N	4.2			
V <sub>IL</sub> Low-I	Low-level input voltage	$V_{CC} = 2 V$	0	Ą	0.5	0		0.5	V
		$V_{CC} = 4.5 V$	0	a de	1.35	0		1.35	
		$V_{CC} = 6 V$	0	5	1.8	0		1.8	
VI	Input voltage		0	50	VCC	0		VCC	V
VO	Output voltage		0	)	VCC	0		VCC	V
t <sub>t</sub> Ir	Input transition (rise and fall) time	$V_{CC} = 2 V$	0		1000	0		1000	ns
		$V_{CC} = 4.5 V$	0		500	0		500	
		$V_{CC} = 6 V$	0		400	0		400	
ТА	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		v <sub>cc</sub>	T <sub>A</sub> = 25°C			SN54HC266	SN74HC266	UNIT	
		INDITIONS		MIN	TYP	MAX	MIN MAX	MIN MAX	UNIT	
ЮН	$V_I = V_{IH} \text{ or } V_{IL},$	AO = ACC	6 V		0.01	0.5	10	5	μA	
V <sub>OL</sub> V <sub>I</sub> = V <sub>IH</sub> or	$V_{OL}$ $V_{I} = V_{IH} \text{ or } V_{IL}$			2 V		0.002	0.1	0.1	0.1	
		r V <sub>IL</sub> = 20 μA	4.5 V		0.001	0.1	0.1	0.1		
			6 V		0.001	0.1	0.1	0.1	V	
		I <sub>OL</sub> = 4 mA	4.5 V		0.17	0.26	0.4	0.33		
		I <sub>OL</sub> = 5.2 mA	6 V		0.15	0.26	0.4	0.33		
lı	$V_{I} = V_{CC} \text{ or } 0$		6 V		±0.1	±100	2 ±1000	±1000	nA	
ICC	$V_{I} = V_{CC} \text{ or } 0,$	I <sup>O</sup> = 0	6 V			2	<b>Q</b> 40	20	μA	
Ci			2 V to 6 V		3	10	10	10	pF	



# SN54HC266, SN74HC266 **QUADRUPLE 2-INPUT EXCLUSIVE-NOR GATES** WITH OPEN-DRAIN OUTPUTS

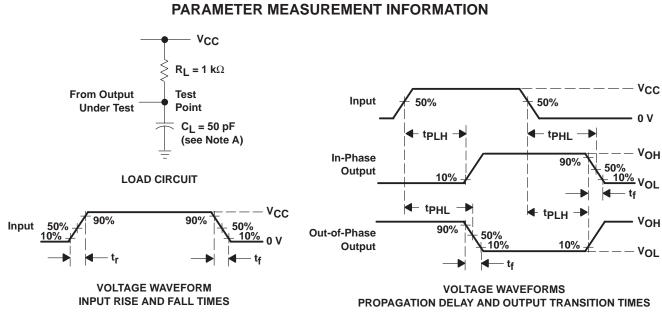
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## switching characteristics over recommended operating free-air temperature range, CL = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	то	Vee	Τį	λ = 25°C	;	SN54HC266	SN74HC266	UNIT
FARAMETER		(OUTPUT)	Vcc	MIN	TYP	MAX	MIN MAX	MIN MAX	UNIT
		2 V		60	125	190	155		
<sup>t</sup> PLH	A or B	Y	4.5 V		13	25	38	31	ns
			6 V		10	23	32	26	
		Y	2 V		60	100	150	125	
<sup>t</sup> PHL	A or B		4.5 V		13	20	30	25	ns
			6 V		10	17	25	21	
	t <sub>t</sub> Y	2	2 V		28	75	<b>0</b> 110	95	
tt		Y	4.5 V		8	15	<b>Q</b> 22	19	ns
			6 V		6	13	19	16	

## operating characteristics, $T_A = 25^{\circ}C$

PARAMETER		TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub> Power dissipation capacitance per gate		No load	35	pF



#### NOTES: A. CL includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>r</sub> = 6 ns, t<sub>f</sub> = 6 ns.
- C. The outputs are measured one at a time with one input transition per measurement.

### Figure 1. Load Circuit and Voltage Waveforms



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